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**The grouping of facial images using agglomerative hierarchical clustering to improve the CBIR based face recognition system**  
 Muhammad Fachrurrozi ; Clara Fin Badillah ; Saparudin ; Junia Erlina ; Erwin ;  
 Mardiana ; Auzan Lazuardi  
 2017 International Conference on Data and Software Engineering (ICoDSE)  
 Year: 2017 | Conference Paper | Publisher: IEEE  
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Abstract (370 Kb)

The grouping of facial images using agglomerative hierarchical clustering to improve the CBIR based face recognition system

Muhammad Fachrurrozi | Clara Fin Badillah | Saparudin | Junia Erlina | Erwin |  
 Mardiana | Auzan Lazuardi

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**Content based image retrieval for multi-objects fruits recognition using k-means and k-nearest neighbor**  
 Erwin ; M. Fachrurrozi ; Ahmad Fiqih ; Bahardiansyah Rua Saputra ;  
 Rachmad Algani ; Anggina Primanita  
 2017 International Conference on Data and Software Engineering (ICoDSE)  
 Year: 2017 | Conference Paper | Publisher: IEEE  
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Abstract (593 Kb)

Content based image retrieval for multi-objects fruits recognition using k-means and k-nearest neighbor

Erwin | M. Fachrurrozi | Ahmad Fiqih | Bahardiansyah Rua Saputra | Rachmad  
 Algani | Anggina Primanita

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